

Notice of References Cited	Application/Control No. 10/581,562		Applicant(s)/Patent Under Reexamination RIEGEL ET AL.	
	Examiner Liam J. Heincer		Art Unit 1796	Page 1 of 3

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Applicant(s)/Patent Under
Reexamination
RIEDEL ET AL.

Examiner

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Art Unit

1796

Page 2 of 3

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	Examiner Liam J. Heincer		Art Unit 1796	Page 3 of 3

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